FOR IMMEDIATE RELEASE

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AEHR TEST SYSTEMS RECEIVES MTX ORDER FROM MEMORY MANUFACTURER

Fremont, CA (March 25, 2004) -- Aehr Test Systems (Nasdaq: AEHR), a leading supplier of semiconductor test and burn-in equipment, today announced it has received an order totaling over $2 million for its new MTX model Fp+ test during burn-in systems. The systems are scheduled to ship in the fourth quarter of fiscal year 2004.

The order is for a turnkey production solution for burn-in and testing of advanced memories. The solution includes the MTX-Fp+ system, performance test boards and automation for loading and unloading devices.

"We believe that the MTX-Fp+ system is ideal for manufacturers who produce DRAM or flash memories, or both," said Carl Buck, vice president of marketing of Aehr Test Systems. "This dual functionality is a cost-effective solution, as it allows manufacturers to use the same capital equipment for test and burn-in as the product mix changes."

The MTX-Fp+ system is an enhanced version of Aehr Test's MTX Massively Parallel Test System. The system adds the capability to burn-in and perform parallel test of flash memories, in addition to its traditional parallel test and burn-in of DRAMs. For both applications, the MTX-Fp+ system burns-in and functionally tests more than 12,000 devices simultaneously. The MTX-Fp+ system makes use of the new, larger PTB-400 Performance Test Board, which increases the system capacity and decreases the testing cost per device under test.

About Aehr Test Systems

Headquartered in Fremont, California, Aehr Test Systems is a leading worldwide provider of systems for burning-in and testing DRAM and logic integrated circuits and has an installed base of more than 2,000 systems worldwide. Aehr Test has developed and introduced several innovative products, including the FOX™, MTX, MAX3 and MAX4 systems, and the DiePak® carrier. The FOX system is a full wafer contact test and burn-in system. The MTX system is a massively parallel test system designed to reduce the cost of memory testing by performing both test and burn-in on thousands of devices simultaneously. The MAX system can effectively burn-in and functionally test complex devices, such as digital signal processors, microprocessors, microcontrollers and systems-on-a-chip. The DiePak carrier is a reusable, temporary package that enables IC manufacturers to perform cost-effective final test and burn-in of bare die. For more information, please visit the Company's Web site at www.aehr.com.

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Safe Harbor Statement

This release contains forward-looking statements that involve risks and uncertainties relating to projections regarding customer demand and acceptance of Aehr Test's products. Actual results may vary from projected results. These risks and uncertainties include, without limitation, acceptance by customers of the MTX technology, acceptance by customers of the MTX-Fp+ systems shipped upon receipt of a purchase order and the ability of new products to meet customer needs or perform as described. See Aehr Test's recent 10-K and 10-Q reports filed with the SEC for a more detailed description of the risks facing our business. The Company disclaims any obligation to update information contained in any forward-looking statement to reflect events or circumstances occurring after the date of this press release.

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